

# High-Side and Low-Side Gate Driver

# **FAN7382**

The FAN7382, a monolithic high and low side gate-drive IC, can drive MOSFETs and IGBTs that operate up to +600 V. **onsemi's** high-voltage process and commonmode noise canceling technique provides stable operation of the high-side driver under high-dv/dt noise circumstances. An advanced level-shift circuit allows high-side gate driver operation up to  $V_S = -9.8~V$  (typical) for  $V_{BS} = 15~V$ . The input logic level is compatible with standard TTL-series logic gates. UVLO circuits for both channels prevent malfunction when  $V_{CC}$  or  $V_{BS}$  is lower than the specified threshold voltage. Output drivers typically source/sink 350 mA/650 mA, respectively, which is suitable for fluorescent lamp ballasts, PDP scan drivers, motor controls, etc.

#### **Features**

- Floating Channels Designed for Bootstrap Operation to +600 V
- Typically 350 mA/650 mA Sourcing/Sinking Current Driving Capability for Both Channels
- Common-Mode dv/dt Noise Canceling Circuit
- Extended Allowable Negative V<sub>S</sub> Swing to -9.8 V for Signal Propagation at V<sub>CC</sub> = V<sub>BS</sub> = 15 V
- V<sub>CC</sub> & V<sub>BS</sub> Supply Range from 10 V to 20 V
- UVLO Functions for Both Channels
- TTL Compatible Input Logic Threshold Levels
- Matched Propagation Delay Below 50 ns
- Output In-phase with Input Signal
- These are Pb-Free Devices

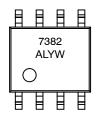




SOIC14 N CASE 751ER

#### **MARKING DIAGRAMS**

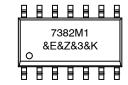
SOIC8



7382 = Device Code
A = Assembly Site
L = Wafer Lot Number
YW = Assembly Start Week

Assembly Start We

#### SOIC14 N



7382M1 = Device Code &E = Designates Space &Z = Assembly Location &3 = 3-Digit Date Code

&K = 2-Digits Lot Run Traceability Code

#### ORDERING INFORMATION

See detailed ordering and shipping information on page 12 of this data sheet

## **Typical Application Circuit**

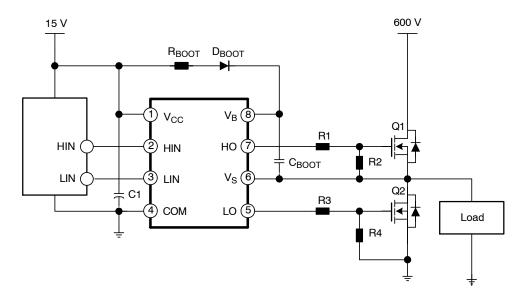


Figure 1. Application Circuit for Half-Bridge

## **Internal Block Diagram**

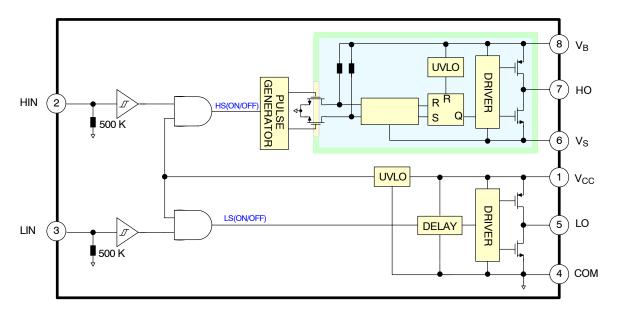
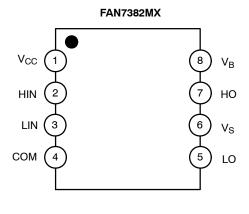


Figure 2. Functional Block Diagram

## **Pin Assignments**



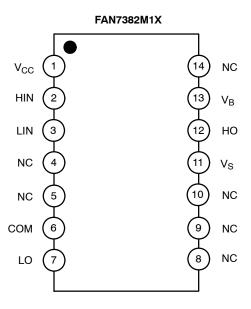


Figure 3. Pin Configuration (Top View)

## **PIN DIFINITIONS**

Name	Description
V <sub>CC</sub>	Low-Side Supply Voltage
HIN	Logic Input for High-Side Gate Driver Output
LIN	Logic Input for Low-Side Gate Driver Output
COM	Logic Ground and Low-Side Driver Return
LO	Low-Side Driver Output
Vs	High-Voltage Floating Supply Return
НО	High-Side Driver Output
V <sub>B</sub>	High-Side Floating Supply

#### **ABSOLUTE MAXIMUM RATINGS**

Parameter	Symbol	Min	Max	Unit
High-Side Offset Voltage	V <sub>S</sub>	V <sub>B</sub> – 25	V <sub>B</sub> + 0.3	V
High-Side Floating Supply Voltage	V <sub>B</sub>	-0.3	625	
High-Side Floating Output Voltage HO	V <sub>HO</sub>	V <sub>S</sub> - 0.3	V <sub>B</sub> + 0.3	
Low-Side and Logic Fixed Supply Voltage	V <sub>CC</sub>	-0.3	25	
Low-Side Output Voltage LO	$V_{LO}$	-0.3	V <sub>CC</sub> + 0.3	
Logic Input Voltage (HIN, LIN)	V <sub>IN</sub>	-0.3	V <sub>CC</sub> + 0.3	
Logic Ground	COM	V <sub>CC</sub> – 25	V <sub>CC</sub> + 0.3	
Allowable Offset Voltage Slew Rate	dV <sub>S</sub> /dt		50	V/ns
Power Dissipation	P <sub>D</sub>	SOIC8	0.625	W
	(Notes 1, 2, 3)	SOIC14 N	1.0	
Junction temperature	$T_J$		150	°C
Storage Temperature	T <sub>STG</sub>		150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Mounted on 76.2 x 114.3 x 1.6 mm PCB (FR-4 glass epoxy material).

- 2. Refer to the following standards:
  - JESD51-2: Integral circuits thermal test method environmental conditions natural convection JESD51-3: Low effective thermal conductivity test board for leaded surface mount packages
- 3. Do not exceed PD under any circumstances.

## THERMAL CHARACTERISTICS

Parameter	Symbol	Min	Max	Unit
Thermal Resistance, Junction-to-Ambient	$\theta_{\sf JA}$	SOIC8	200	°C/W
		SOIC14 N	110	

#### RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Min	Max	Unit
High-Side Floating Supply Voltage	V <sub>B</sub>	V <sub>S</sub> + 10	V <sub>S</sub> + 20	V
High-Side Floating Supply Offset Voltage	V <sub>S</sub>	6 – V <sub>CC</sub>	600	V
High-Side (HO) Output Voltage	V <sub>HO</sub>	V <sub>S</sub>	V <sub>B</sub>	V
Low-Side (LO) Output Voltage	$V_{LO}$	COM	V <sub>CC</sub>	V
Logic Input Voltage (HIN, LIN)	V <sub>IN</sub>	COM	V <sub>CC</sub>	V
Low-Side Supply Voltage	V <sub>CC</sub>	10	20	V
Ambient Temperature	T <sub>A</sub>	-40	125	°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

#### **ELECTRICAL CHARACTERISTICS**

 $V_{BIAS}$  ( $V_{CC}$ ,  $V_{BS}$ ) = 15.0 V,  $T_A$  = 25°C, unless otherwise specified. The  $V_{IN}$  and  $I_{IN}$  parameters are referenced to COM. The  $V_O$  and  $I_O$  parameters are referenced to  $V_S$  and COM and are applicable to the respective outputs HO and LO.

Parameter	Test Condition	Symbol	Min	Тур	Max	Unit
V <sub>CC</sub> and V <sub>BS</sub> Supply Under-Voltage Positive Going Threshold		V <sub>CCUV+</sub> V <sub>BSUV+</sub>	8.2	9.2	10.0	V
V <sub>CC</sub> and V <sub>BS</sub> Supply Under-Voltage Positive Going Threshold		V <sub>CCUV</sub> - V <sub>BSUV</sub> -	7.6	8.7	9.6	V
V <sub>CC</sub> Supply Under-Voltage Lockout Hysteresis		V <sub>CCUVH</sub> V <sub>BSUVH</sub>		0.6		V
Offset Supply Leakage Current	V <sub>B</sub> = V <sub>S</sub> = 600 V	I <sub>LK</sub>			50	μΑ
Quiescent V <sub>BS</sub> Supply Current	V <sub>IN</sub> = 0 V or 5 V	I <sub>QBS</sub>		45	120	μΑ
Quiescent V <sub>CC</sub> Supply Current	V <sub>IN</sub> = 0 V or 5 V	I <sub>QCC</sub>		70	180	μΑ
Operating V <sub>BS</sub> Supply Current	f <sub>IN</sub> = 20 kHz, rms value	I <sub>PBS</sub>			600	μΑ
Operating V <sub>CC</sub> Supply Current	f <sub>IN</sub> = 20 kHz, rms value	I <sub>PCC</sub>			600	μΑ
Logic "1" Input Voltage		V <sub>IH</sub>	2.9			V
Logic "0" input voltage		V <sub>IL</sub>			0.8	V
High-Level Output Voltage, V <sub>BIAS</sub> - V <sub>O</sub>	I <sub>O</sub> = 20 mA	V <sub>OH</sub>			1.0	V
Low-Level Output Voltage, VO		V <sub>OL</sub>			0.6	V
Logic "1" Input Bias Current	V <sub>IN</sub> = 5 V	I <sub>IN+</sub>		10	20	μΑ
Logic "0" Input Bias Current	V <sub>IN</sub> = 0 V	I <sub>IN</sub> _		1.0	2.0	μΑ
Output High Short-Circuit Pulsed Current	$V_O$ = 0 V, $V_{IN}$ = 5 V with PW < 10 $\mu$ s	I <sub>O+</sub>	250	350		mA
Output Low Short-Circuit Pulsed Current	$V_O$ = 15 V, $V_{IN}$ = 0 V with PW < 10 $\mu s$	I <sub>O-</sub>	500	650		mA
Allowable Negative VS Pin Voltage for HIN Signal Propagation to HO		V <sub>S</sub>		-9.8	-7.0	V

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product

performance may not be indicated by the Electrical Characteristics if operated under different conditions.

## **DYNAMIC ELECTRICAL CHARACTERISTICS**

 $V_{BIAS}$  ( $V_{CC}$ ,  $V_{BS}$ ) = 15.0 V,  $V_{S}$  = COM,  $C_{L}$  = 1000 pF and,  $T_{A}$  = 25°C, unless otherwise specified.

Parameter	Test Condition	Symbol	Min	Тур	Max	Unit
Turn-On Propagation Delay	V <sub>S</sub> = 0 V	t <sub>on</sub>	100	170	300	ns
Turn-Off Propagation Delay	V <sub>S</sub> = 0 V or 600 V (Note 4)	t <sub>off</sub>	100	200	300	ns
Turn-On Rise Time		t <sub>r</sub>	20	60	140	ns
Turn-Off Fall Time		t <sub>f</sub>		30	80	ns
Delay Matching, HS & LS Turn-On/Off		MT			50	ns

4. This parameter guaranteed by design.

#### TYPICAL CHARACTERISTICS

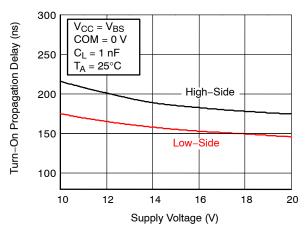


Figure 4. Turn-On Propagation Delay vs. Supply Voltage

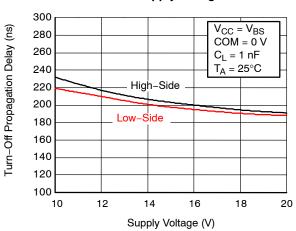


Figure 6. Turn-Off Propagation Delay vs. Supply Voltage

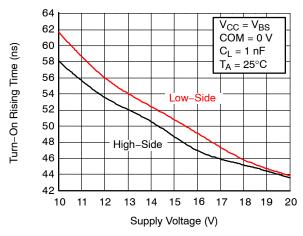


Figure 8. Turn-On Rising Time vs. Supply Voltage

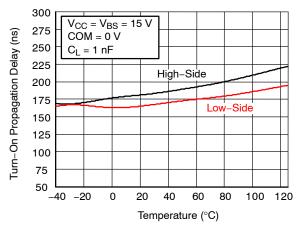


Figure 5. Turn-On Propagation Delay vs. Temperature

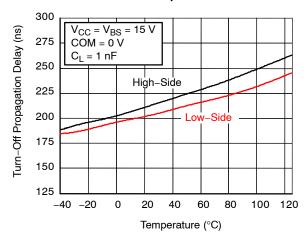


Figure 7. Turn-Off Propagation Delay vs. Temperature

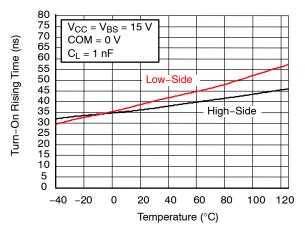


Figure 9. Turn-On Rising Time vs. Temperature

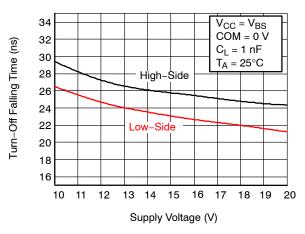


Figure 10. Turn-Off Falling Time vs. Supply Voltage

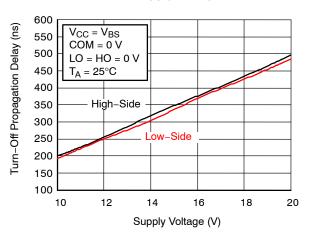


Figure 12. Output Sourcing Current vs. Supply Voltage

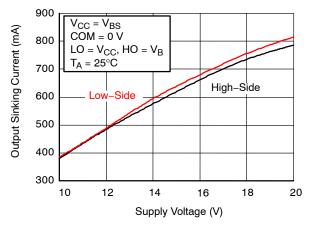


Figure 14. Output Sinking Current vs. Supply Voltage

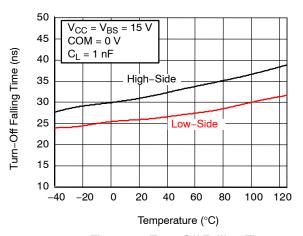


Figure 11. Turn-Off Falling Tim vs. Temperature

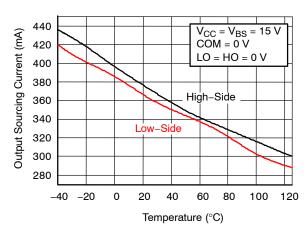


Figure 13. Output Sourcing Current vs. Temperature

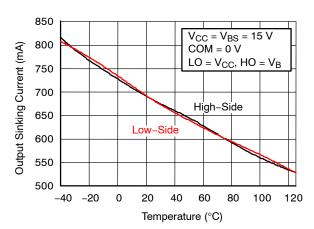


Figure 15. Output Sinking Current vs. Temperature

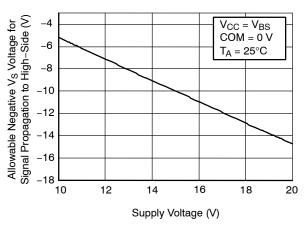


Figure 16. Allowable Negative V<sub>S</sub> Voltage for Signal Propagation to High Side vs. Supply Voltage

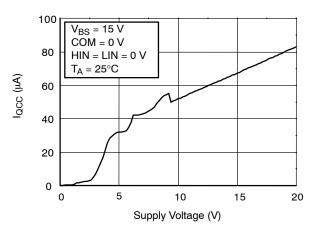


Figure 18. I<sub>QCC</sub> vs. Supply Voltage

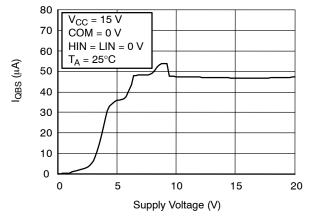


Figure 20. I<sub>QBS</sub> vs. Supply Voltage

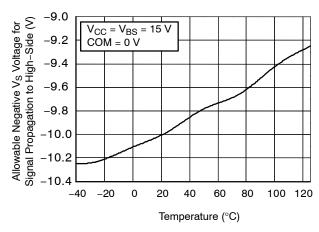


Figure 17. Allowable Negative  $V_{\mbox{\scriptsize S}}$  Voltage for Signal Propagation to High Side vs. Temperature

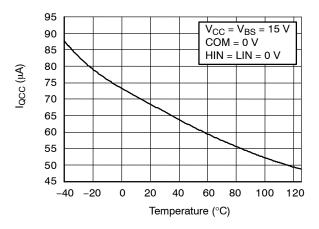


Figure 19. I<sub>QCC</sub> vs. Temperature

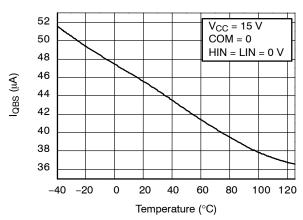


Figure 21. I<sub>QBS</sub> vs. Temperature

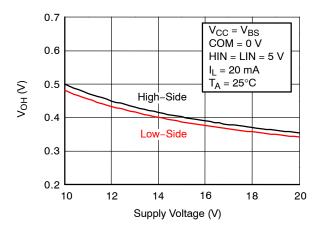


Figure 22. High-Level Output Voltage vs. Supply Voltage

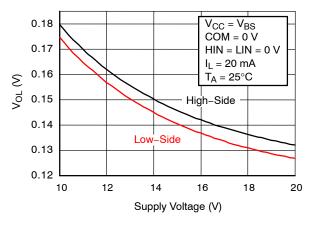


Figure 24. Low-Level Output Voltage vs. Supply Voltage

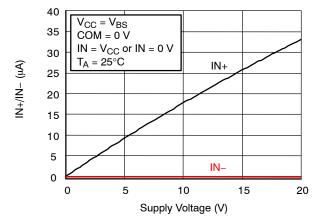


Figure 26. Input Bias Current vs. Supply Voltage

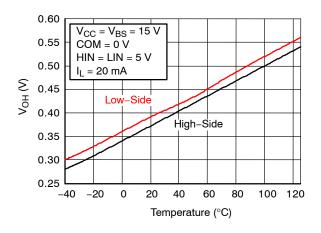


Figure 23. High-Level Output Voltage vs. Temperature

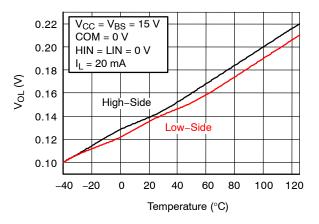


Figure 25. Low-Level Output Voltage vs. Temperature

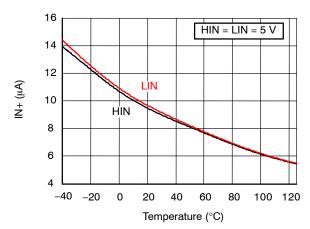


Figure 27. Input Bias Current vs. Temperature

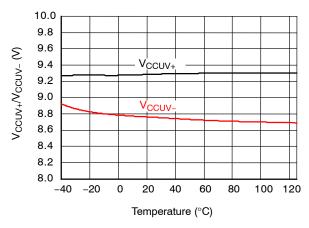


Figure 28. V<sub>CC</sub> UVLO Threshold Voltage vs. Temperature

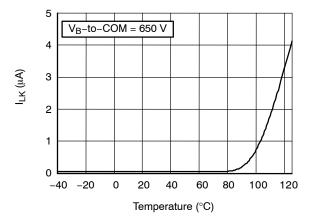


Figure 30.  $V_B$  to COM Leakage Current vs. Temperature

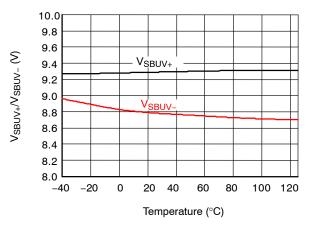


Figure 29. V<sub>BS</sub> UVLO Threshold Voltage vs. Temperature

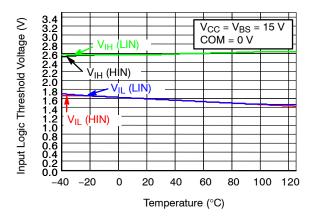
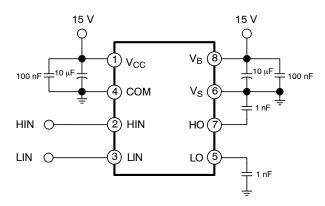


Figure 31. Input Logic Threshold Voltage vs. Temperature



HIN LIN LIN LO

Figure 32. Switching Time Test Circuit

Figure 33. Input / Output Timing Diagram

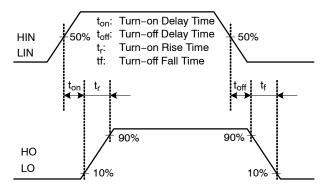


Figure 34. Switching Time Waveform Definition

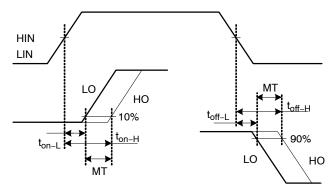


Figure 35. Delay Matching Waveform Definition

## **ORDERING INFORMATION**

Part Number	Operating Temperature Range	Package	Shipping <sup>†</sup>
FAN7382MX (Note 5)	−40°C ~125°C	SOIC8 (Pb-Free)	3000 / Tape & Reel
FAN7382M1X (Note 5)		SOIC14 N (Pb-Free)	3000 / Tape & Reel

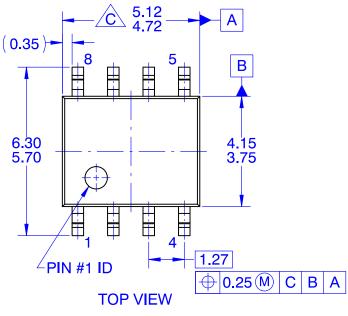
<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

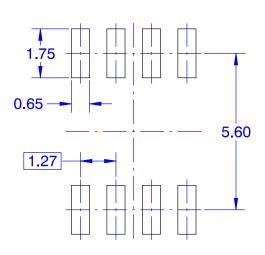
5. These devices passed wave soldering test by JESD22A–111.



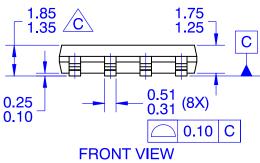
#### SOIC8 CASE 751EG ISSUE O

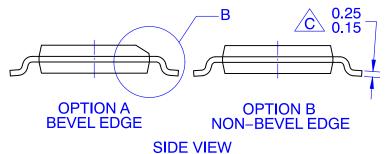
**DATE 30 SEP 2016** 





LAND PATTERN RECOMMENDATION





## NOTES: UNLESS OTHERWISED SPECIFIED

- A. THIS PACKAGE CONFORMS TO JEDEC MS-012 VARIATION A EXCEPT WHERE NOTED.
- B. ALL DIMENSIONS ARE IN MILLIMETERS



- D. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR EXTRUSIONS.
- E. LAND PATTERN AS PER IPC SOIC127P600X175–8M

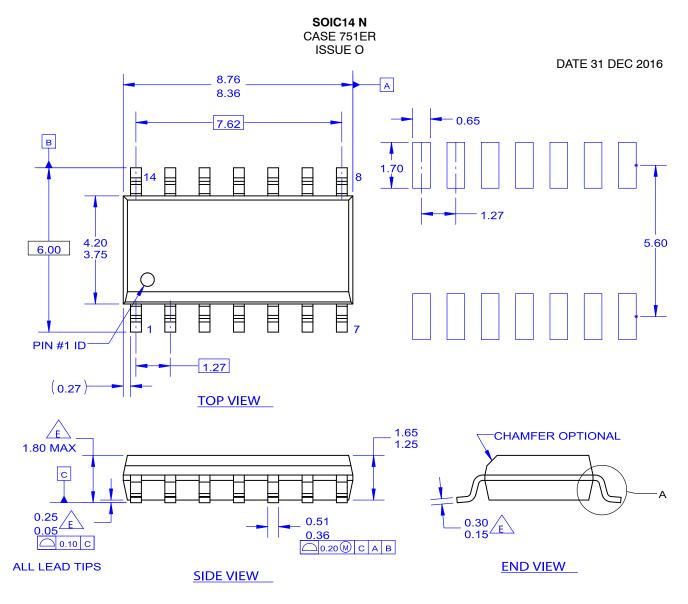
PLANE	- BEVEL	R0.10
		0.25
8° 4° - SEATING PLANE	(1.04)	- - - 0.80 - 0.30
DETA		

**GAGE** 

DETAIL "B" SCALE 2:1

DOCUMENT NUMBER:	98AON13741G	Electronic versions are uncontrolled except when accessed directly from the Document Reported versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	SOIC8	•	PAGE 1 OF 1	

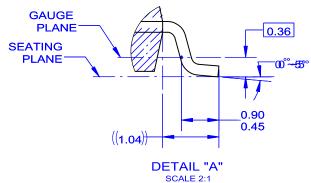
ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.



#### NOTES: UNLESS OTHERWISE SPECIFIED

- A. THIS PACKAGE REFERENCE TO JEDEC MS-012 VARIATION AB.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR EXTRUSIONS.
- D. DIMENSIONS AND TOLERANCES AS PER ASME \( \times \) Y14.5-1994.

 $\angle \mathtt{E} \setminus$  OUT OF JEDEC STANDARD VALUE.



DOCUMENT NUMBER:	98AON13761G	Electronic versions are uncontrolled except when accessed directly from the Document Rep Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	SOIC14 N		PAGE 1 OF 1	

ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

onsemi, ONSEMI., and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. Onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using onsemi products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications provided by onsemi. "Typical" parameters which may be provided in onsemi data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. onsemi does not convey any license under any of its intellectual property rights nor the rights of others. onsemi products are not designed, intended, or authorized for use as a critical component in life support systems or any EDA class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer p

## PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT: Email Requests to: orderlit@onsemi.com

TECHNICAL SUPPORT North American Technical Support: Voice Mail: 1 800-282-9855 Toll Free USA/Canada Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support: Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative

onsemi Website: www.onsemi.com